WEST

Freeform Search

Database:	US Patents Full-Text Database US Pre-Grant Publication Full-Text Database JPO Abstracts Database EPO Abstracts Database Derwent World Patents Index IBM Technical Disclosure Bulletins					
Term: Display: Generate:	Documents in Display Format: TI Starting with Number 1 Hit List • Hit Count • Side by Side • Image					
Search Clear Help Logout Interrupt Main Menu Show S Numbers Edit S Numbers Preferences Cases						

Search History

DATE: Wednesday, September 25, 2002 Printable Copy Create Case

Set Name	Query	H	lit Count	Set Name	
side by side				result set	
DB=USPT; $PLUR=YES$; $OP=OR$					
<u>L10</u>	L9 and substrate and silicon		1250	<u>L10</u>	
<u>L9</u>	"(110)".clm.		10952	<u>L9</u>	
<u>L8</u>	L7 and ((hydrogenated near4 nitride) or (oxynitride))		94	<u>L8</u>	
<u>L7</u>	glass with ((passivation or base or underlayer or blocking) near4 (layer or film)) and (TFT\$1 or (thin adj film))		2025	<u>L7</u>	
<u>L6</u> .	fonash.in.	¥,	18	<u>L6</u>	
<u>L5</u>	L4 not (semiconductor and energy and laboratory)	Ī	105	<u>L5</u>	
<u>L4</u>	L3 and semiconductor		365	<u>L4</u>	
<u>L3</u>	L2 and oxide		1174	<u>L3</u>	
<u>L2</u>	L1 and (nickel with solution)		1318	<u>L2</u>	
<u>L1</u>	amorphous same crystal\$8		40932	<u>L1</u>	

END OF SEARCH HISTORY